

<b>Notice of References Cited</b>	Application/Control No. 10/023,167	Applicant(s)/Patent Under Reexamination OP DE BEEK ET AL.	
	Examiner John B Strege	Art Unit 2625	Page 1 of 1

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	C	US-6,289,235	09-2001	Webber et al.	600/426
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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